Signetics

74AC/ACT11475

9-Wide Transceiver/Register with Dual Enable; 3-State; INV

Objective Specification

ACL Products

FEATURES

- **Combines '245 and '374 type functions in one chip**
- **9-wide transceiver with D-type flip-flops**
- **3-State buffers**
- **Output capability: ±24 mA**
- **CMOS (AC) and TTL (ACT) voltage level inputs**
- **50Ω incident wave switching**
- **Center-pin V_{CC} and ground configuration to minimize high-speed switching noise**
- **I_{CC} category: MSI**

DESCRIPTION

The 74AC/ACT11475 high-performance CMOS devices combine very high speed and high output drive comparable to the most advanced TTL families.

The 74AC/ACT11475 device contains two sets of D-type flip-flops for temporary storage of data flowing in either direction. Dual clock (CP_{AB}, CP_{BA}) and Output Enable ($\overline{OE}_{AB}$, $\overline{OE}_{BA}$) inputs are provided for each register to permit independent control of inputting and outputting in either direction of data flow.

GENERAL INFORMATION

SYMBOL	PARAMETER	CONDITIONS T_A = 25°C; GND = 0V; V_{CC} = 5.0V		TYPICAL AC	TYPICAL ACT	UNIT
t_{PLH}/t_{PHL}	Propagation delay CP_{XX} to $\overline{A}_n$ or $\overline{B}_n$	C_L = 50pF		5.3	7.1	ns
C_{PD}	Power dissipation capacitance per register[1]	f = 1MHz; C_L = 50pF	Enabled	200	200	pF
			Disabled	50	50	
C_{IN}	Input capacitance	V_I = 0V or V_{CC}		4.5	4.5	pF
$C_{I/O}$	I/O capacitance	$V_{I/O}$ = 0V or V_{CC}; Disabled		12	12	pF
I_{LATCH}	Latch-up current	Per Jedec JC40.2 Standard 17		500	500	mA
f_{MAX}	Maximum clock frequency	C_L = 50pF		125	125	MHz

Note:

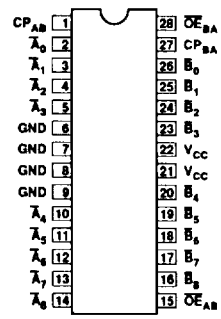
1. C_{PD} is used to determine the dynamic power dissipation (P_D in µW):
   $P_D = C_{PD} \times V_{CC}^2 \times f_I + \Sigma (C_L \times V_{CC}^2 \times f_O)$ where:
   f_I = input frequency in MHz, C_L = output load capacitance in pF,
   f_O = output frequency in MHz, V_{CC} = supply voltage in V,
   $\Sigma (C_L \times V_{CC}^2 \times f_O)$ = sum of outputs

ORDERING INFORMATION

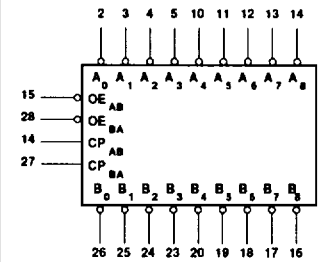
PACKAGES	TEMPERATURE RANGE	ORDER CODE
28-pin plastic DIP (300mil-wide)	-40°C to +85°C	74AC11475N 74ACT11475N
28-pin plastic SO (300mil-wide)	-40°C to +85°C	74AC11475D 74ACT11475D

PIN CONFIGURATION

N and D Packages



LOGIC SYMBOL



LOGIC SYMBOL (IEEE/IEC)

In progress

PIN DESCRIPTION

PIN NUMBER	SYMBOL	NAME AND FUNCTION
1	CP_{AB}	A-to-B clock
27	CP_{BA}	B-to-A clock
15	$\overline{OE}_{AB}$	A-to-B output enable input (active Low)
28	$\overline{OE}_{BA}$	B-to-A output enable input (active Low)
2, 3, 4, 5, 10, 11, 12, 13, 14	$\overline{A}_0$ - $\overline{A}_8$	Data inputs/outputs (A side)
26, 25, 24, 23, 20, 19, 18, 17, 16	$\overline{B}_0$ - $\overline{B}_8$	Data inputs/outputs (B side)
6, 7, 8, 9	GND	Ground (0V)
21, 22	V_{CC}	Positive supply voltage

FUNCTION TABLE

INPUTS			OUTPUTS	STATUS
$\overline{OE}_{xx}$	CP_{xx}	Data		
H	X	X	Z	Latch register and disable outputs
L	↑	l h	H L	Enable and read register

H = High voltage level
h = High state present one setup time before the Low-to-High transition
L = Low voltage level
= Low state present one setup time before the Low-to-High transition
↑ = Low-to-High clock transition
X = Don't care
Z = High-impedance state

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	74AC11475			74ACT11475			UNIT
		Min	Nom	Max	Min	Nom	Max	
V_{CC}	DC supply voltage	3.0[1]	5.0	5.5	4.5	5.0	5.5	V
V_I	Input voltage	0		V_{CC}	0		V_{CC}	V
V_O	Output voltage	0		V_{CC}	0		V_{CC}	V
$\Delta t/\Delta v$	Input transition rise or fall rate	0		10	0		10	ns/V
T_A	Operating free-air temperature	-40		+85	-40		+85	°C

NOTE:
1. No electrical or switching characteristics are specified at $V_{CC} < 3V$. Operation between 2V and 3V is not recommended, but within that range, a device output will maintain a previously established logic state.

ABSOLUTE MAXIMUM RATINGS[1]

SYMBOL	PARAMETER	TEST CONDITIONS	RATING	UNIT
V_{CC}	DC supply voltage		-0.5 to+7.0	V
I_{IK} or V_I	DC input diode current[2]	$V_I < 0$	-20	mA
		$V_I > V_{CC}$	20	
	DC input voltage		-0.5 to V_{CC} +0.5	V
I_{OK} or V_O	DC output diode current[2]	$V_O < 0$	-50	mA
		$V_O > V_{CC}$	50	
	DC output voltage		-0.5 to V_{CC} +0.5	V
I_O	DC output source or sink current per output pin	V_O = 0 to V_{CC}	±50	mA
I_{CC} or I_{GND}	DC V_{CC} current		±225	mA
	DC ground current		±225	
T_{STG}	Storage temperature		-65 to 150	°C
P_{TOT}	Power dissipation per package Plastic DIP	Above 70°C:derate linearly by 8mW/K	500	mW
	Power dissipation per package Plastic surface mount (SO)	Above 70°C:derate linearly by 6mW/K	400	mW

NOTES:
1. Stresses beyond those listed may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
2. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

DC ELECTRICAL CHARACTERISTICS

SYMBOL	PARAMETER	TEST CONDITIONS		V_{CC}	74AC11475				74ACT11475				UNIT
					T_A = +25°C		T_A = -40°C to +85°C		T_A = +25°C		T_A = -40°C to +85°C		
				V	Min	Max	Min	Max	Min	Max	Min	Max	
V_{IH}	High-level input voltage			3.0	2.10		2.10						V
				4.5	3.15		3.15		2.0		2.0		
				5.5	3.85		3.85		2.0		2.0		
V_{IL}	Low-level input voltage			3.0		0.90		0.90					V
				4.5		1.35		1.35		0.8		0.8	
				5.5		1.65		1.65		0.8		0.8	
V_{OH}	High-level output voltage	V_I = V_{IL} or V_{IH}	I_{OH} = -50μA	3.0	2.9		2.9						V
				4.5	4.4		4.4		4.4		4.4		
				5.5	5.4		5.4		5.4		5.4		
			I_{OH} = -4mA	3.0	2.58		2.48						
			I_{OH} = -24mA	4.5	3.94		3.8		3.94		3.8		
				5.5	4.94		4.8		4.94		4.8		
			I_{OH} = -75mA[1]	5.5			3.85				3.85		
V_{OL}	Low-level output voltage	V_I = V_{IL} or V_{IH}	I_{OL} = 50μA	3.0		0.1		0.1					V
				4.5		0.1		0.1		0.1		0.1	
				5.5		0.1		0.1		0.1		0.1	
			I_{OL} = 12mA	3.0		0.36		0.44					
			I_{OL} = 24mA	4.5		0.36		0.44		0.36		0.44	
				5.5		0.36		0.44		0.36		0.44	
			I_{OL} = 75mA[1]	5.5				1.65				1.65	
I_I	Input leakage current	V_I = V_{CC} or GND		5.5		±0.1		±1.0		±0.1		±1.0	μA
I_{OZ}	3-State output off-state current	V_I = V_{IL} or V_{IH}; V_O = V_{CC} or GND		5.5		±0.5		±5.0		±0.5		±5.0	μA
I_{CC}	Quiescent supply current	V_I = V_{CC} or GND, I_O = 0		5.5		8.0		80		8.0		80	μA
ΔI_{CC}	Supply current, TTL inputs High[2]	One input at 3.4V, other inputs at V_{CC} or GND		5.5						0.9		1.0	mA

NOTES:
1. Not more than one output should be tested at a time, and the duration of the test should not exceed 10ms.
2. This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0V or V_{CC}.